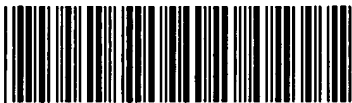


Search Notes

Application/Control No.

10/726,328

Examiner

Matthew W. Such

Applicant(s)/Patent under
Reexamination

DERDERIAN ET AL.

Art Unit

2891

SEARCHED

Class	Subclass	Date	Examiner
438	665,962, 964	3/14/2007	MWS
427	185,191	3/14/2007	MWS
427	192,201	3/14/2007	MWS
427	205,241	3/14/2007	MWS
427	215-217	3/14/2007	MWS

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
Claims interference text searched		3/14/2007	MWS

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST Text Search: ALD and/or colloid\$2, suspens\$4, slurry, nitride	3/14/2007	MWS
EAST 438/597-685 crossed with ALD and/or colloid\$2, suspens\$4, slurry, nitride	3/14/2007	MWS
EAST 427/123-124,126.1,189-191,217 crossed with ALD and or colloid\$2, suspens\$4, slurry, nitride	3/14/2007	MWS
NPL Search Google Scholar and Google ALD, colloidal, nano- or micro sphere lithography	3/14/2007	MWS
EAST Text Search: nano- or micro- sphere lithography	3/14/2007	MWS